

PATENT
4444-0129P

IN THE U.S. PATENT AND TRADEMARK OFFICE

Applicant: Yin-Chun HUANG et al. Conf.:
Appl. No.: NEW Group:
Filed: December 4, 2003 Examiner:
For: CHIP WITH MEASURING RELIABILITY AND A
METHOD THEREOF

PRELIMINARY AMENDMENT

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

December 4, 2003

Sir:

The following preliminary amendments and remarks are respectfully submitted in connection with the above-identified application.

This amendment includes Amendments to the Specification; and Remarks.